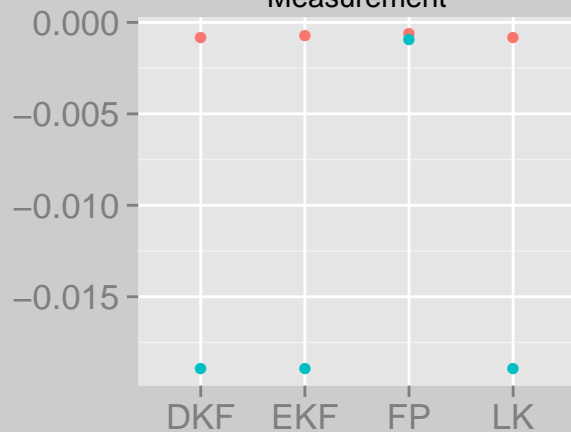


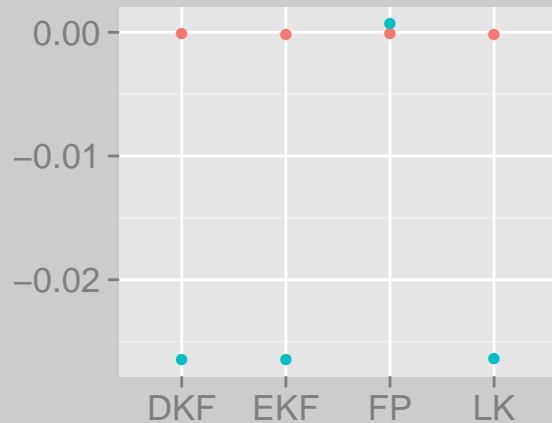
Bias
Measurement



Process Noise

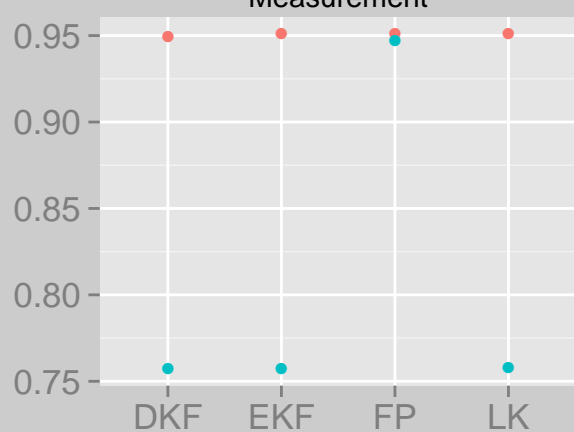


Time Series

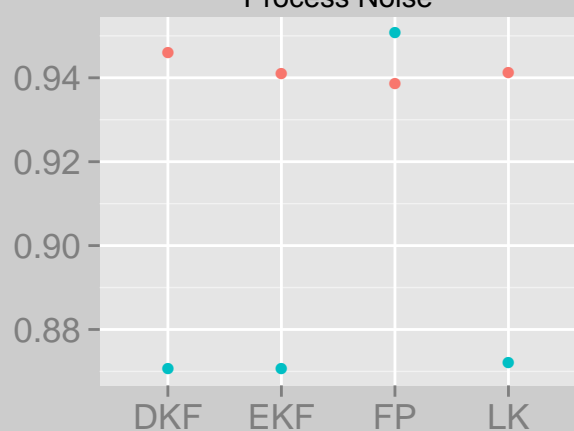


FittedIC

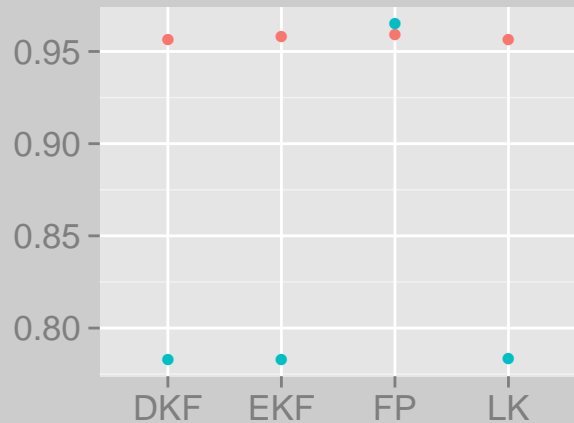
Coverage Rates
Measurement



Process Noise

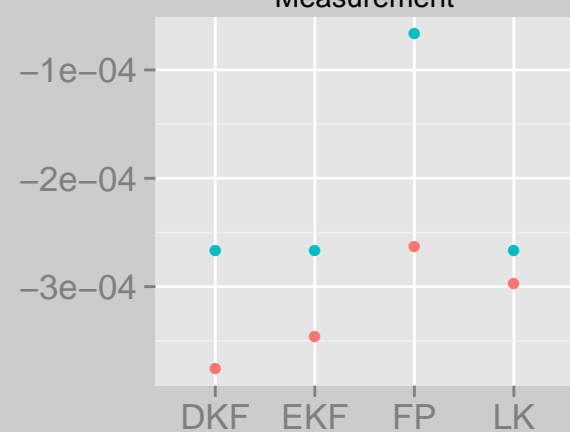


Time Series

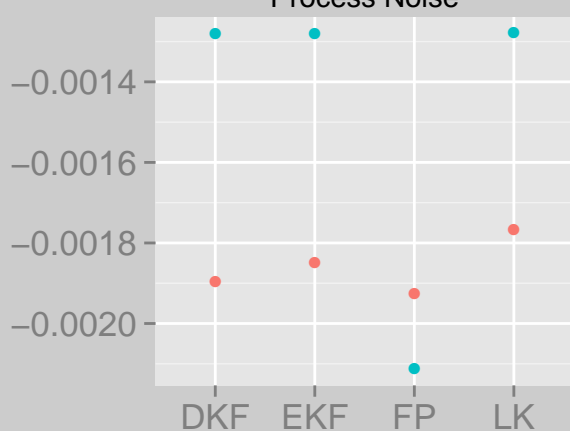


FittedIC

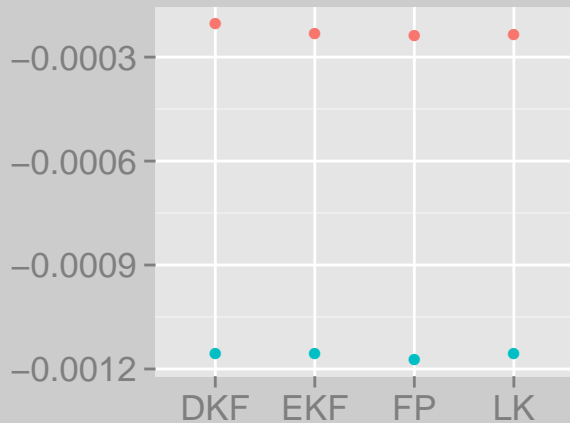
SD - SE
Measurement



Process Noise



Time Series



FittedIC